

January 2006

# FDB8860

# N-Channel Logic Level PowerTrench® MOSFET 30V, 80A, 2.6m $\Omega$

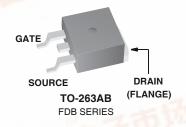
#### **Features**

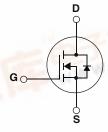
- $R_{DS(ON)} = 1.9 \text{m}\Omega$  (Typ),  $V_{GS} = 5 \text{V}$ ,  $I_D = 80 \text{A}$
- $Q_{g(5)} = 89nC (Typ), V_{GS} = 5V$
- Low Miller Charge
- Low Q<sub>RR</sub> Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant

## **Applications**

- 12V Automotive Load Control
- Start / Alternator Systems
- Electronic Power Steering Systems
- ABS
- DC-DC Converters







Units

# **MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain to Source Voltage	30	V
V <sub>GS</sub>	Gate to Source Voltage	±20	V
	Drain Current Continuous (V <sub>GS</sub> = 10V, T <sub>C</sub> < 163°C)	80	Α
ID	Continuous (V <sub>GS</sub> = 5V, T <sub>C</sub> < 162°C)	80	Α
	Continuous ( $V_{GS} = 10V$ , $T_C = 25$ °C, with $R_{\theta JA} = 43$ °C/W)	31	Α
	Pulsed	Figure 4	Α
E <sub>AS</sub>	SinglePulseAvalancheEnergy (Note1)	947	mJ
D	Power Dissipation	306	W
$P_{D}$	Derate above 25°C	2.04	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to +175	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance Junction to Case	0.49	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (Note 2)	62	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263,1in <sup>2</sup> copper pad area	43	°C/W

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB8860	FDB8860	TO-263AB	330mm	24mm	800units

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Parameter

Off Characteristics							
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1mA, V_{GS} = 0$	0V	30	-	-	V
I <sub>DSS</sub> Zero Gate Voltage D	Zoro Coto Voltago Droin Current	$V_{DS} = 24V$		-	-	1	μА
	Zero Gate Voltage Drain Current	$V_{GS} = 0V$	$T_J = 150$ °C	-	-	250	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

**Test Conditions** 

Min

Тур

Max

#### **On Characteristics**

Symbol

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.7	3	V
	I <sub>D</sub> = 80A, V <sub>GS</sub> = 10V	-	1.6	2.3		
	R <sub>DS(ON)</sub> Drain to Source On Resistance	$I_D = 80A, V_{GS} = 5V$	-	1.9	2.6	
R <sub>DS(ON)</sub>		$I_D = 80A, V_{GS} = 4.5V$	-	2.1	2.7	mΩ
	$I_D = 80A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	-	2.5	3.6		

## **Dynamic Characteristics**

C <sub>ISS</sub>	Input Capacitance	V 45V V	$V_{DS} = 15V, V_{GS} = 0V,$		9460	12585	pF
Coss	Output Capacitance	$V_{DS} = 15V, V_{GS}$ f = 1MHz			1710	2275	pF
C <sub>RSS</sub>	Reverse Transfer Capacitance	1 - 1141112		-	1050	1575	pF
$R_G$	Gate Resistance	f = 1MHz	f = 1MHz		1.8	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V <sub>GS</sub> = 0V to 10V		-	165	214	nC
$Q_{g(5)}$	Total Gate Charge at 5V	V <sub>GS</sub> = 0V to 5V	],, ,_,,	-	89	115	nC
$Q_{g(TH)}$	Threshold Gate Charge	V <sub>GS</sub> = 0V to 1V	$V_{DD} = 15V$ $I_{D} = 80A$	-	9.1	12	nC
$Q_{gs}$	Gate to Source Gate Charge		$I_0 = 60A$ $I_0 = 1.0mA$	-	26	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau		ig = 1.0117 (	-	18	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge			-	33	-	nC

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Switching	g Characteristics					
t <sub>(on)</sub>	Turn-On Time		-	-	340	ns
t <sub>d(on)</sub>	Turn-On Delay Time		-	14	-	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 15V, I_D = 80A$	-	213	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 5V, R_{GS} = 1\Omega$	-	79	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	49	-	ns
t <sub>off</sub>	Turn-Off Time		-	-	192	ns

#### **Drain-Source Diode Characteristics**

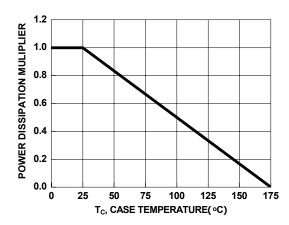
V	Source to Drain Diode Voltage	I <sub>SD</sub> = 80A			1.25	V
$V_{SD}$	Source to Drain blode Voltage	I <sub>SD</sub> = 40A	•	-	1.0	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 80A$ , $dI_{SD}/dt = 100A/\mu s$	-	-	43	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_{SD} = 80A$ , $dI_{SD}/dt = 100A/\mu s$	-	-	29	nC

**Notes:** 1: Starting  $T_J = 25^{\circ}C$ , L = 0.47 mH,  $I_{AS} = 64 \text{A}$ ,  $V_{DD} = 30 \text{V}$ ,  $V_{GS} = 10 \text{V}$ . 2: Pulse width = 100s

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/
All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

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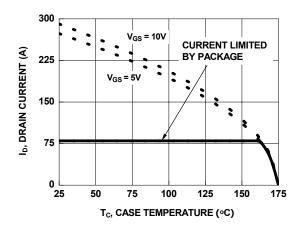


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs
Case Temperature

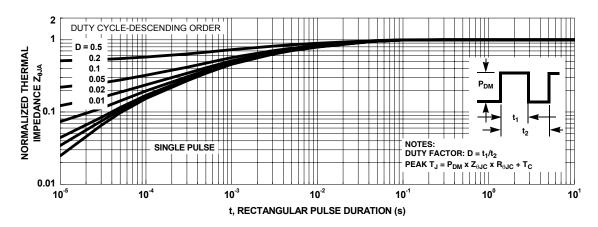


Figure 3. Normalized Maximum Transient Thermal Impedance

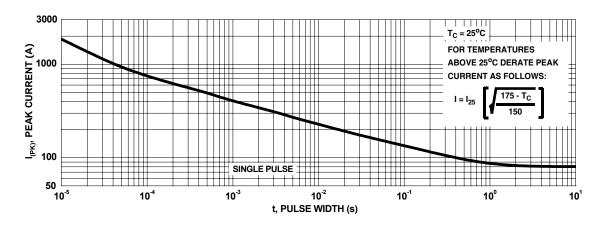
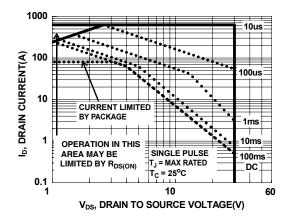


Figure 4. Peak Current Capability

# Typical Characteristics $T_J = 25$ °C unless otherwise noted



IAS, AVALANCHE CURRENT 0.1 10 100 1000 10000 t<sub>AV</sub>, TIME IN AVALANCHE (ms)

 $t_{AV} = (L/R)ln[(I_{AS}*R)/(1.3*RATED BV_{DSS} - V_{DD}) +1]$ 

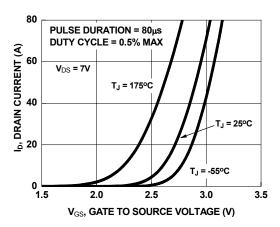
If R = 0 t<sub>AV</sub> = (L)(I<sub>AS</sub>)/(1.3\*RATED BV<sub>DSS</sub>

500

₹

Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515 Figure 6. Unclamped Inductive Switching Capability



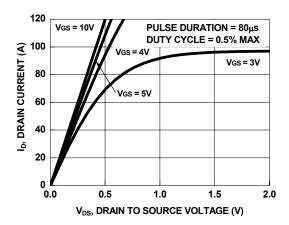
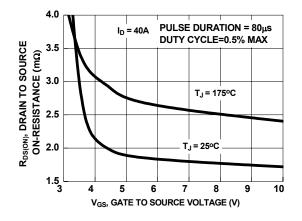


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



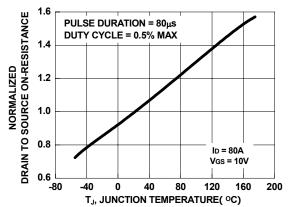


Figure 9. Drain to Source On-Resistance Variation vs Gate to Source Voltage

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

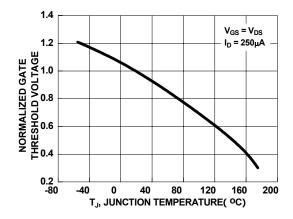


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

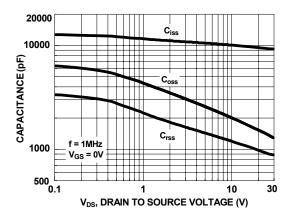


Figure 13. Capacitance vs Drain to Source Voltage

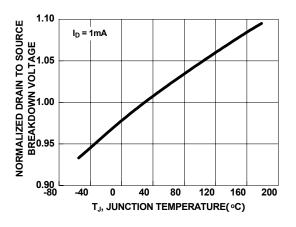


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

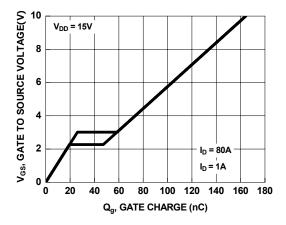


Figure 14. Gate Charge vs Gate to Source Voltage

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